

<b>Notice of References Cited</b>	Application/Control No. 10/049,522		Applicant(s)/Patent Under Reexamination HEYMANN ET AL.	
	Examiner Ajay M. Bhatia		Art Unit 2145	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,351,467 B1	02-2002	Dillon, Douglas M.	370/432
*	B	US-2004/0073631 A1	04-2004	Keorkunian et al.	709/219
*	C	US-2005/0027788 A1	02-2005	Koopmans et al.	709/200
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.